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MESSAGE

Re: Serial No. 09/378,666  
As indicated in the message I left in your voicemail, I am enclosing proposed claim amendments. As you and I previously discussed, Applicants request an interview in person with you. Applicants propose October 8, 2003 (Wednesday) at 2 pm. If the proposed date and time is not suitable, please let us know of another date and time, preferably during the week of Oct. 6-10. Thanks.

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David John Watson et al., Serial No. 09/378,666

1. A particle size distribution analysis apparatus comprising a sample measurement zone defining a sample of particles, a light emitting means for providing a source of light incident upon the sample measurement zone, and at least a first detection means for measuring light levels in the apparatus at particular scattering angles and output a signal to a computation means for calculating said particle size distribution enabling the particle size distribution of particles contained within said sample to be determined, wherein said computation means [calculates, in use, said particle size distribution taking into account, for each of said scattering angles,] is arranged to substantially completely compensate for the reflection, by at least one window of said measurement zone, of light that has previously been scattered by said particles, at each of said scattering angles when calculating said particle size distribution.

14. A method of improving the accuracy of a particle size distribution calculation performed by illuminating a sample with light from a light emitting means and measuring an amount of light scattered by the sample comprising providing at least a first detection means and [calculating the particle size distribution taking into account] substantially completely compensating for reflection by at least one window of a measurement zone of light, that has previously been scattered by the particles at at least two scattering angles.

1. A particle size distribution analysis apparatus comprising a sample measurement zone defining a sample of particles, a light emitting means for providing a source of light incident upon the sample measurement zone, and at least a first detection means for measuring light levels in the apparatus at particular scattering angles and output a signal to a computation means for calculating said particle size distribution enabling the particle size distribution of particles contained within said sample to be determined, wherein [~~said computation means calculates, in use, said particle size distribution taking into account, for each of said scattering angles, reflection by at least one window of said measurement zone, of light that has previously been scattered by said particles~~] , in use, light scattered by said particles is reflected from at least one window of said measurement zone, said computation means being arranged to substantially completely compensate for light scattered by said particles and reflected from said at least one window, at each of said scattering angles, when calculating said particle size distribution.

14. A method of improving the accuracy of a particle size distribution calculation performed by illuminating a sample with light from a light emitting means and measuring an amount of light scattered by the sample comprising providing at least a first detection means and [calculating the particle size distribution taking into account] substantially completely compensating for reflection by at least one window of a measurement zone of light, that has previously been scattered by the particles at at least two scattering angles.